

Specification for Approval					
	Date:	2014/7/15	Halegen	(Pb) Cer	rtificate
	Customer :	台慶	Halogen-fre	Pb-free Gree	en Partner
	TAI-TECH P/N: CPI20	1610PF-2R2M-1A2			
	CUSTOMER P/N:				
	DESCRIPTION:				
	QUANTITY:	pcs			
REI	MARK:				
	Customer A	oproval Feedback			
		技股份有限公			
	TAI-TECH Advanc	ed Electronics Co., I	<u>_td</u>		
西北臺慶科技股份有限公司 TAI-TECH Advanced Electro Headquarter:	pnics Co., Ltd	Sales Dep.			
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http://www.tai-tech.com.tw E-mail: sales@tai-tech.com.tw		管哲頎	林巧盈		
東莞臺慶精密電子有限公司 DONGGUAN TAI-TECH ADVANCED ELECTRONICS CO., LTD JITIGANG MANAGEMENT DISTRICT, HUANGJIANG, DONGGUAN, GUANGDONG, CHINA TEL: #86-769-3365488 FAX: #86-769-3366896 E-mail: twnwe@pub.dgnet.gd.cn Office: 金亨國際有限公司 KAMHENG INTERNATIONAL LIMITED TEL: #86-852-25772033 FAX: #86-852-28817778 臺慶精密電子(昆山)有限公司 TAI-TECH ADVANCED ELECTRONICS(KUNSHAN) CO., LTD SHINWHA ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA		Eric Guan	Emily Lin		
		R&D Center			
		APPROVED	CHECKED	DRAWN]
		楊祥忠 Mike Xana	羅培君	張嘉玲	
TEL: +86-512-57619396 FAX: +86- E-mail: hui@tai-tech.com.tw Office:	512-57619688	Mike Yang	Peijun Lo	Alin Chang	
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TAI-TECH

High Current Ferrite Chip Inductor (Lead Free)

CPI201610PF-2R2M-1A2

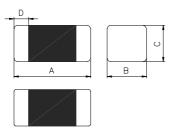
		ECN HIS		Г	
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN
1.0	13/06/06	變更可靠度條件	楊祥忠	羅培君	張嘉玲
2.0	14/01/24	變更電鍍錫層厚度 3.0um min.=>3.5um min.	楊祥忠	羅培君	張嘉玲
備					
註					

High Current Ferrite Chip Inductor (Lead Free) CPI201610PF-2R2M-1A2

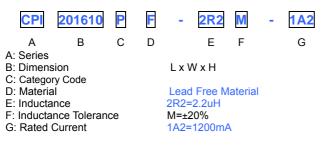
1.Features

- 1. 2.0x1.6 mm and 1 mm in height (very compact size): CAE and fine printing technology made this compact size possible
- 2. Stable minimum DC resistance in the class.
- 3. High speed mounting: Using SMT mounter makes less than a second mounting possible.
- 4. Excellent mounting strength by SMD chip making.
- 5. Reduced noise over 2/3 of coil inductor by optimal design of CAD Completely lead-free product and support lead-free solder.

2. Dimensions

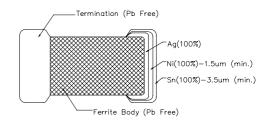


3. Part Numbering



Chip Size		
Α	2.00±0.20	
В	1.60±0.20	
С	1.00 max.	
D	0.50±0.30	

Units: mm



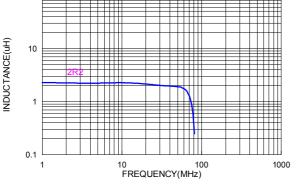
4.Specification

Tai-Tech	Inductance(uH)	Test Frequency	Rated Current	DCR	SRF
Part Number	inductance(un)	(MHz)	(mA) max.	()	(MHz) min.
CPI201610PF-2R2M-1A2	2.2±20%	1	1200	0.12±30%	70

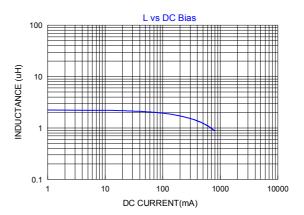
Rated current: based on temperature rise test.

L vs Freq 100 +

Inductance-Frequency Characteristics



Inductance VS DC Bias Current





5. Reliability and Test Condition

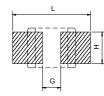
Item	Performance	Test Condition
Operating Temperature	-40~+105 (Including self-temperature rise)	
Transportation Storage Temperature	-40~+105 (on board)	For long storage conditions, please see the Application Notice
Inductance (Ls)		Agilent4291 Agilent E4991
Q Factor	Refer to standard electrical characteristics list	Agilent4287 Agilent16192
DC Resistance		Agilent 4338
Rated Current		DC Power Supply Over Rated Current requirements, there will be some risk
Temperature Rise Test	Rated Current < 1A ΔT 20 Max Rated Current 1A ΔT 40 Max	 Applied the allowed DC current. Temperature measured by digital surface thermometer.
Resistance to Soldering Heat	Appearance : No damage. Impedance : within±15% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	Preheat: 150 ,60sec. Solder: Sn99.5%-Cu0.5% Solder temperature: 260±5 Flux for lead free: Rosin. 9.5% Temperature ramp/immersion and immersion rate: 25±6 mm/s Dip time: 10±1sec. Depth: completely cover the termination.
Solderability	More than 95% of the terminal electrode should be covered with solder. Preheating Dipping Natural cooling 245°C 4 ± 1 second $50^{\circ}C - 4\pm 1$ second 4 ± 1	Preheat: 150 ,60sec. Solder: Sn99.5%-Cu0.5% Solder temperature: 245±5 Flux for lead free: Rosin. 9.5% Depth: completely cover the termination. Dip time: 4±1sec.
Terminal strength	Appearance : No damage. Impedance : within±15% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value.	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles) Component mounted on a PCB apply a force (>805:1kg <=0805:0.5kg)to the side of a device being tested. This force shall be applied for 60 +1 seconds. Also the force shall be applied gradually as not to shock the component being tested.
Bending	Appearance : No damage. Impedance : within±10% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	Shall be mounted on a FR4 substrate of the following dimensions:>=0805:40x100x1.2mm <0805:40x100x0.8mm Bending depth:>=0805:1.2mm <0805:0.8mm Duration of 10 sec for a min.
Vibration Test	Appearance : No damage. Impedance : within±15% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles) Oscillation Frequency: 10 2K 10Hz for 20 minutes Equipment : Vibration checker Total Amplitude1.52mm±10% Testing Time : 12 hours(20 minutes, 12 cycles each of 3 orientations), Test condition:
Shock	Appearance : No damage. Impedance : within±15% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	Peak Normal Velocity Type Value duration Wave form change (g's) (D) (ms) Wave form (Vi)ft/sec SMD 1,500 0.5 Half-sine 15.4
		Lead 100 6 Half-sine 12.3

Item	Performance	Test Condition
Life test	Appearance: no damage. Impedance: within±15% of initial value.	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles) Temperature: 125±2 (bead), 85±2 (inductor) Applied current: rated current. Duration: 1000±12hrs. Measured at room temperature after placing for 24±2 hrs.
Load Humidity	 Inductance: within±10% of initial value. Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value 	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles) Humidity: 85±2%R.H. Temperature: 85±2 . Duration: 1000hrs Min. with 100% rated current. Measured at room temperature after placing for 24±2 hrs.
Thermal shock	Appearance: no damage. Impedance: within±15%of initial value. Inductance: within±10%of initial value. Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles) Condition for 1 cycle Step1: -40±2 30±5 min. Step2: 25±2 0.5min Step3: +105±2 30±5min. Number of cycles: 500 Measured at room temperature after placing for 24±2 hrs.
Insulation Resistance	IR>1GΩ	Chip Inductor Only Test Voltage:100±10%V for 30Sec.

6.Soldering and Mounting

6-1. Recommended PC Board Pattern

	Chip Size						Pattern	
Series	Туре	A(mm)	B(mm)	C(mm)	D(mm)	L(mm)	G(mm)	H(mm)
CPI	201610	2.0±0.2	1.6±0.20	1.0 max	0.5±0.30	3.00	1.00	1.60



PC board should be designed so that products can prevent damage from mechanical stress when warping the board.

6-2. Soldering

Mildly activated rosin fluxes are preferred. The terminations are suitable for re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools. Note.

If wave soldering is used ,there will be some risk.

Re-flow soldering temperatures below 240 degrees, there will be non-wetting risk

6-2.1 Lead Free Solder re-flow:

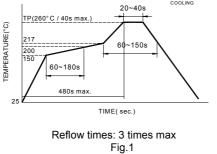
Recommended temperature profiles for lead free re-flow soldering in Figure 1. (Refered to J-STD-020C)

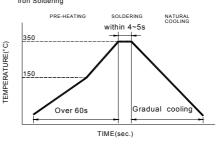
Upper limit

Recommendable

6-2.2 Soldering Iron:

Products attachment with a soldering iron is discouraged due to the inherent process control limitations. In the event that a soldering iron must be employed the following precautions are recommended. for Iron Soldering in Figure 2. Preheat circuit and products to 150 Never contact the ceramic with the iron tip Use a 20 watt soldering iron with tip diameter of 1.0mm tip temperature (max) 1.0mm tip diameter (max) Limit soldering time to 4~5sec. 350 Iron Soldering Reflow Soldering PRE-HEATING SOLDERING NATURAL PRE-HEATING SOLDERING NATURAL COOLING within 4~5s 20~40s





Iron Soldering times : 1 times max Fig.2

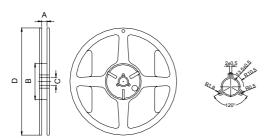
6-2.3 Solder Volume:

Accordingly increasing the solder volume, the mechanical stress to product is also increased. Exceeding solder volume may cause the failure of mechanical or electrical performance. Solder shall be used not to be exceed as shown in right side:

Minimum fillet height = soldering thickness + 25% product height

7. Packaging Information

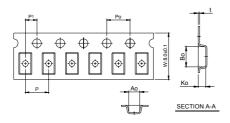
7-1. Reel Dimension



Туре	A(mm)	B(mm)	C(mm)	D(mm)
7"x8mm	8.4±0.5	60±2	13.5±0.5	178±2

7-2.1 Tape Dimension / 8mm

Material of taping is plastic



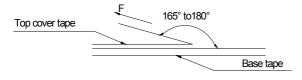
Series	Size	P(mm)	Po(mm)	P1(mm)	Bo(mm)	Ao(mm)	Ko(mm)	t(mm)
CPI	201610	4.0±0.1	4.0±0.1	2.0±0.1	2.50±0.10	1.90±0.10	1.25±0.10	0.23±0.05

TAI-TECH

7-3. Packaging Quantity

Chip size	201610
Reel	3000
Inner box	15000
Middle box	75000
Carton	150000

7-4. Tearing Off Force



The force for tearing off cover tape is 15 to 60 grams in the arrow direction under the following conditions.

TBM01-140700620 P6

Room Temp.	Room Humidity	Room atm	Tearing Speed
()	(%)	(hPa)	mm/min
5~35	45~85	860~1060	300

Application Notice

Storage Conditions(component level)

- To maintain the solder ability of terminal electrodes:
- 1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- 2. Temperature and humidity conditions: Less than 40 and 60% RH.
- 3. Recommended products should be used within 12 months form the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.

Transportation

- 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
- 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
- 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.





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Test Report

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

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(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

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以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as):

樣品名稱(Sample Description)	:	FERRITE CHIP BEAD INDUCTOR ARRAY MCF MCM YMV SERIES
樣品型號(Style/Item No.)	:	FERRITE CHIP BEAD INDUCTOR ARRAY MCF MCM YMV SERIES
收件日期(Sample Receiving Date)	:	2013/12/05
測試期間(Testing Period)	:	2013/12/05 TO 2013/12/12
	===	

测试结果(Test Results) : 請見下一頁 (Please refer to next pages).



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<u> 测試結果(Test Results)</u>

測試部位(PART NAME)No.1	:	整體混測	(MIXED ALL PARTS)
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测試項目 (Test Items)	單位 (Unit)	测試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
鎬 / Cadmium (Cd)	mg/kg	參考IEC 62321-5: 2013方法, 以感應耦合電 漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.
鉛 / Lead (Pb)	mg/kg	参考IEC 62321-5: 2013方法,以感應耦合電 漿原子發射兆譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.
汞 / Mercury (Hg)	mg/kg	参考IEC 62321-4: 2013方法,以感應耦合電 漿原子發射光譜儀檢測. / With reference to IEC 62321-4: 2013 and performed by ICP-AES.	2	n.d.
六價貉 / Hexavalent Chromium Cr(VI)		参考IEC 62321: 2008方法,以UV-VIS桧测. / With reference to IEC 62321: 2008 and performed by UV-VIS.	2	n.d.
鈹 / Beryllium (Bc)	mg/kg	參考US EPA 3052方法,以感應耦合電漿原子 發射光譜儀檢測. / With reference to US EPA Method 3052. Analysis was performed by ICP-AES.	2	n.d.
纬 / Antimony (Sb)	mg/kg	參考US EPA 3052方法,以感應耦合電漿原子 發射光譜儀檢測. / With reference to US EPA Method 3052. Analysis was performed by ICP-AES.	2	n.d.

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) 潮試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
全氟辛烷磺酸 / Perfluorooctane sulfonates (PFOS-Acid, Metal Salt, Amide)	mg/kg	参考US EPA 3550C: 2007方法,以液相層析/ 質譜儀檢測. / With reference to US EPA 3550C: 2007. Analysis was performed by LC/MS.	10	n.d.
全氟辛酸 / PFOA (CAS No.: 335-67- 1)	mg/kg	参考US EPA 3550C: 2007方法,以液相層析/ 質譜儀檢測. / With reference to US EPA 3550C: 2007. Analysis was performed by LC/MS.	10	n.d.
六溴環十二烷及所有主要被辨列出的異 構物 / Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified (α - HBCDD, β - HBCDD, γ - HBCDD) (CAS No.: 25637-99-4 and 3194-55-6 (134237-51-7, 134237-50-6, 134237- 52-8))	mg/kg	参考IEC 62321: 2008方法,以氣相層析/質 譜儀檢測. / With reference to IEC 62321: 2008 method. Analysis was performed by GC/MS.	5	n.đ.
鄰苯二甲酸甲苯基丁酯 / BBP (Benzyl butyl phthalate) (CAS No.: 85-68- 7)	%	參考EN 14372, 以氣相層析/質譜儀檢測之. / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二(2-乙基己基)酯 / DEHP (Di-(2-ethylhexyl)phthalate) (CAS No.: 117-81-7)	%	参考EN 14372, 以氣相層析/質譜儀檢測之. / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二異癸酯 / DIDP (Di- isodecyl phthalate) (CAS No.: 26761-40-0; 68515-49-1)	%	參考EN 14372, 以氣相層析/質譜儀檢測之. / With reference to EN 14372. Analysis was performed by GC/MS.	0.01	n.d.
鄭苯二甲酸二異壬酯 / DINP (Di- isononyl phthalate) (CAS No.: 28553-12-0; 68515-48-0)	%	参考EN 14372, 以氣相層析/質譜儀檢測之. / With reference to EN 14372. Analysis was performed by GC/MS.	0.01	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
鄰苯二甲酸二正辛酯 / DNOP (Di-n- octyl phthalate) (CAS No.: 117-84- 0)	%	参考EN 14372, 以氣相層析/質譜儀檢測之. / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No.: 84-74-2)	%	參考EN 14372, 以氣相層析/質譜儀檢測之. / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二異丁酯 / DIBP (Di- isobutyl phthalate) (CAS No.: 84- 69-5)	%	參考EN 14372, 以氣相層析/質譜儀檢測之. / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鹵素 / Halogen 鹵素 (氟) / Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg	參考BS EN 14582:2007, 以離子層祈儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素(氣)/ Halogen-Chlorine(Cl) (CAS No.: 22537-15-1)	mg/kg	参考BS EN 14582:2007, 以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素(溴)/ Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg	參考BS EN 14582:2007, 以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素 (碘) / Halogen-Iodine (I) (CAS No.: 14362-44-8)	mg/kg	参考BS EN 14582:2007,以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.

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測試報告 Test Report^{^{*}}

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) 測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値	結果 (Result)
		(mernou)	(MDL)	No.1
多溴聯苯總和 / Sum of PBBs	mg/kg		-	n.d.
一溴聯苯 / Monobromobiphenyl	mg/kg		5	n.d.
二溴聯苯 / Dibromobiphenyl	mg/kg		5	n.d.
三溴聯苯 / Tribromobiphenyl	mg/kg		5	n.d.
四溴聯苯 / Tetrabromobiphenyl	mg/kg		5	n.d.
五溴聯苯 / Pentabromobiphenyl	mg/kg		5	n.d.
六溴聯苯 / Hexabromobiphenyl	mg/kg		5	n.d.
七溴聯苯 / Heptabromobiphenyl	mg/kg		5	n.d.
へ溴聯苯 / Octabromobiphenyl	mg/kg		5	n.d.
九溴聯苯 / Nonabromobiphenyl	mg/kg		5	n.d.
十溴聯苯 / Decabromobiphenyl	mg/kg	參考IEC 62321: 2008方法,以氣相層析/質	5	n.d.
多溴聯苯醚總和 / Sum of PBDEs	mg/kg	譜儀檢測. / With reference to IEC 62321: 2008 and performed by GC/MS	-	n.d.
一溴聯苯醚 / Monobromodiphenyl ether	mg/kg		5	n.d.
二溴聯苯醚 / Dibromodiphenyl ether	mg/kg		5	n.d.
三溴聯苯醚 / Tribromodiphenyl ether	mg/kg		5	n.d.
四溴聯苯醚 / Tetrabromodiphenyl ether	mg/kg		5	n.d.
五溴聯苯醚 / Pentabromodiphenyl ether	mg/kg		5	n.d.
六溴聯苯醚 / Hexabromodiphenyl ether	mg/kg		5	n.d.
七溴聯苯醚 / Heptabromodiphenyl ether	mg/kg		5	n.d.
へ溴聯苯醚 / Octabromodiphenyl ether	mg/kg		5	n.d.
九溴聯苯醚 / Nonabromodiphenyl ether	mg/kg		5	n.d.
十溴聯苯醚 / Decabromodiphenyl ether	mg/kg		5	n.d.

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備註(Note):

- 1. mg/kg = ppm; 0.1wt% = 1000ppm
- 2. n.d. = Not Detected (未檢出)
- 3. MDL = Method Detection Limit (方法偵測極限值)
- 4. "-" = Not Regulated (無規格値)
- 5. 樣品的測試是基於申請人要求混合測試,報告中的混合測試結果不代表其中個别單一材質的含量. (The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

PFOS参考資訊(Reference Information): 持久性有機污染物 POPs - (EU) 757/2010

PFOS濃度在物質或製備中不得超過0.001%(10ppm),在半成品、成品或零部件中不得超過0.1%(1000ppm),在紡織品或 塗層材料中不得超過1µg/m²。

(Outlawing PFOS as substances or preparations in concentrations above 0.001% (10ppm), in semi-finished products or articles or parts at a level above 0.1%(1000ppm), in textiles or other coated materials above $1\mu g/m^2$.)

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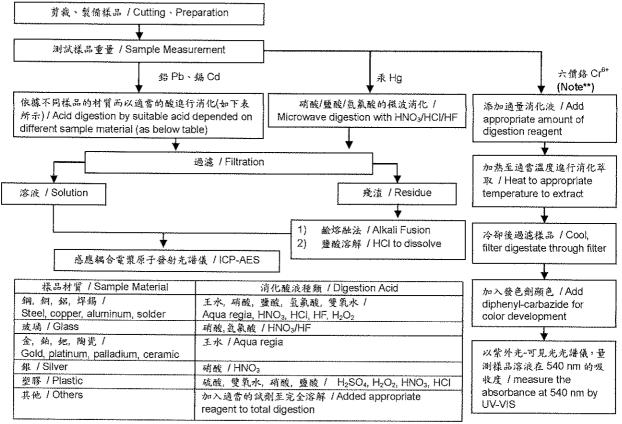
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CHINA) 1) 根據以下的流程圖之條件,樣品已完全溶解。(六價錄測試方法除外) / These samples were

dissolved totally by pre-conditioning method according to below flow chart. (Cr⁶⁺ test method excluded)

- 2) 测试人員:楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 3) 测试負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



Note** (For IEC 62321)

 針對非金屬材料加入鹼性消化液,加熱至 90~95℃ 萃取. / For non-metallic material, add alkaline digestion reagent and heat to 90~95℃.

(2) 針對金屬材料加入純水,加熱至沸騰萃取, / For metallic material, add pure water and heat to boiling.

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Test Report

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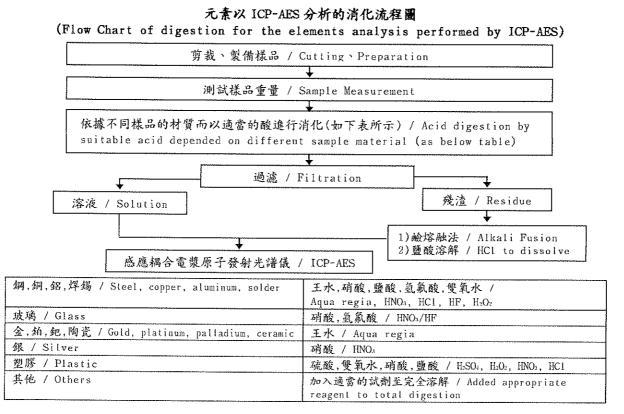
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- 1) 根據以下的流程圖之條件,樣品已完全溶解。 / These samples were dissolved totally by pre-conditioning method according to below flow chart.
- 2) 測試人員:楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 3) 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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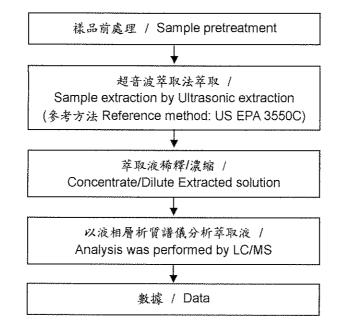
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全氟辛酸/全氟辛烷磺酸分析流程圖 / PFOA/PFOS analytical flow chart

- 測試人員: 翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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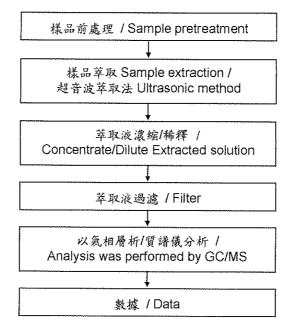
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六溴環十二烷分析流程圖 / HBCDD analytical flow chart

- 測試人員:翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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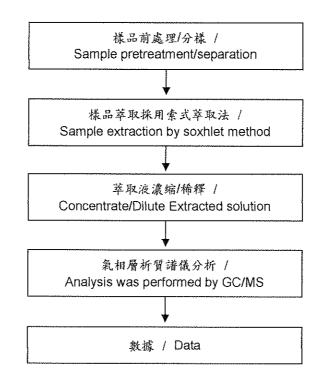
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可塑劑分析流程圖 / Analytical flow chart of phthalate content

🗯 测试人员:翁赐彬 / Name of the person who made measurement: Roman Wong

🔳 测試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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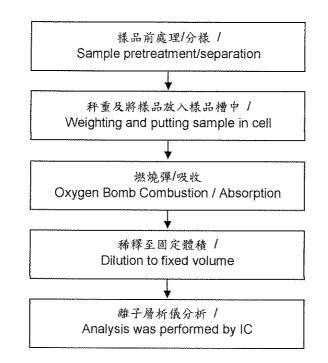
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鹵素分析流程圖 / Analytical flow chart of halogen content

- 测试人员:陳恩臻 / Name of the person who made measurement: Rita Chen
- 🗯 测試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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Test Report

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(東莞臺慶精密電子有限公司 / TAI-TECH ADVANCED ELECTRONICS (DONGGUAN) CO. LTD.)

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

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(江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

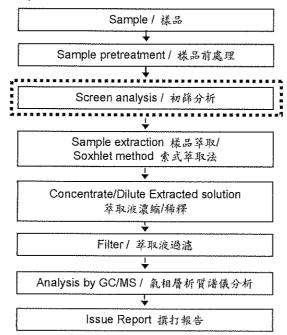
■ 测试人員:翁賜彬 / Name of the person who made measurement: Roman Wong

■ 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang

初次测试程序 / First testing process -------

選擇性篩檢程序 / Optional screen process = = = = = = = =

確認程序 / Confirmation process - - - - →



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SGS Taiwan Ltd. 台灣接触對技戰份有限公司 33, Wu Chuan Rd., New Taipei Industrial Park, New Taipei City, Taiwan / 新北市新北產樂園區五鞭路33號 ++886 (02)2299 3279 f+886 (02)2299 3237 www.sgs.tw



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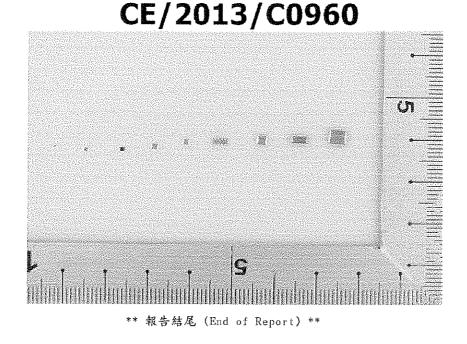
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* 照片中如有箭頭標示,則表示為實際檢測之樣品/部位。*

(The tested sample / part is marked by an arrow if it's shown on the photo.)



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